## Notice of References Cited

Application/Control No. 10/707,734	Reexamination	Applicant(s)/Patent Under Reexamination CHENG ET AL.		
Examiner	Art Unit			
Sved Y. Hasan	2621	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0164156	11-2002	Bilbrey, Brett	386/112
*	В	US-6,798,980	09-2004	Seo, Beom Joo	386/125
*	С	US-6,767,253	07-2004	Werner et al.	439/638
*	D	US-2005/0169114	08-2005	Ahn, Hosung	369/007
*	E	US-2003/0090515	05-2003	Chang et al.	345/745
*	F	US-2005/0128889	06-2005	Keller et al.	369/030.04
*	G	US-7,003,214	02-2006	Ando et al.	386/96
*	Н	US-6,987,924	01-2006	Fujita et al.	386/46
*	1	US-6,226,441	05-2001	Hartung et al.	386/46
*	J	US-5,974,015	10-1999	lizuka et al.	386/96
	K	US-			·
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country .	Name	Classification
	N					
	0			· ·	•	
	Р					
	Q		·		-	
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.